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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	150
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx24-ftq176

Microsemi Corporate Headquarters
One Enterprise, Aliso Viejo,
CA 92656 USA
Within the USA: +1 (800) 713-4113
Outside the USA: +1 (949) 380-6100
Fax: +1 (949) 215-4996
Email: sales.support@microsemi.com
www.microsemi.com

About Microsemi

Microsemi Corporation (Nasdaq: MSCC) offers a comprehensive portfolio of semiconductor and system solutions for aerospace & defense, communications, data center and industrial markets. Products include high-performance and radiation-hardened analog mixed-signal integrated circuits, FPGAs, SoCs and ASICs; power management products; timing and synchronization devices and precise time solutions, setting the world's standard for time; voice processing devices; RF solutions; discrete components; enterprise storage and communication solutions, security technologies and scalable anti-tamper products; Ethernet solutions; Power-over-Ethernet ICs and midspans; as well as custom design capabilities and services. Microsemi is headquartered in Aliso Viejo, California, and has approximately 4,800 employees globally. Learn more at www.microsemi.com.

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Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • **Voltage Support of MX Devices**

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

Each I/O cell has three boundary-scan register cells, each with a serial-in, serial-out, parallel-in, and parallel-out pin. The serial pins are used to serially connect all the boundary-scan register cells in a device into a boundary-scan register chain, which starts at the TDI pin and ends at the TDO pin. The parallel ports are connected to the internal core logic tile and the input, output and control ports of an I/O buffer to capture and load data into the register to control or observe the logic state of each I/O.

Figure 14 • **42MX IEEE 1149.1 Boundary Scan Circuitry**

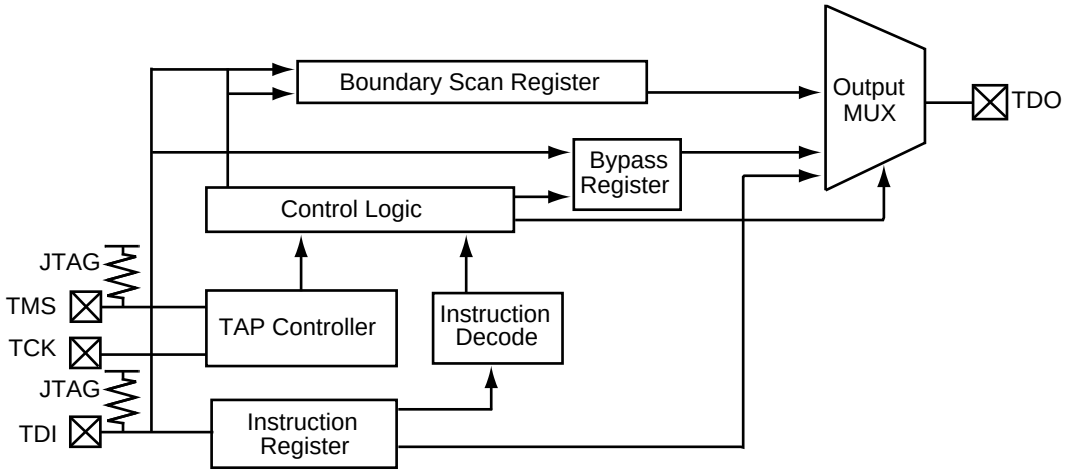


Table 9 • **Test Access Port Descriptions**

Port	Description
TMS (Test Mode Select)	Serial input for the test logic control bits. Data is captured on the rising edge of the test logic clock (TCK).
TCK (Test Clock Input)	Dedicated test logic clock used serially to shift test instruction, test data, and control inputs on the rising edge of the clock, and serially to shift the output data on the falling edge of the clock. The maximum clock frequency for TCK is 20 MHz.
TDI (Test Data Input)	Serial input for instruction and test data. Data is captured on the rising edge of the test logic clock.
TDO (Test Data Output)	Serial output for test instruction and data from the test logic. TDO is set to an Inactive Drive state (high impedance) when data scanning is not in progress.

Table 10 • **Supported BST Public Instructions**

Instruction	IR Code (IR2.IR0)	Instruction Type	Description
EXTEST	000	Mandatory	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
SAMPLE/PRELOAD	001	Mandatory	Allows a snapshot of the signals at the device pins to be captured and examined during operation
HIGH Z	101	Optional	Tristates all I/Os to allow external signals to drive pins. See the IEEE Standard 1149.1 specification.
CLAMP	110	Optional	Allows state of signals driven from component pins to be determined from the Boundary-Scan Register. See the IEEE Standard 1149.1 specification for details.
BYPASS	111	Mandatory	Enables the bypass register between the TDI and TDO pins. The test data passes through the selected device to adjacent devices in the test chain.

3.4.9 JTAG Mode Activation

The JTAG test logic circuit is activated in the Designer software by selecting **Tools > Device Selection**. This brings up the Device Selection dialog box as shown in the following figure. The JTAG test logic circuit can be enabled by clicking the “Reserve JTAG Pins” check box. The following table explains the pins' behavior in either mode.

Figure 15 • **Device Selection Wizard**

Table 11 • **Boundary Scan Pin Configuration and Functionality**

Reserve JTAG	Checked	Unchecked
TCK	BST input; must be terminated to logical HIGH or LOW to avoid floating	User I/O
TDI, TMS	BST input; may float or be tied to HIGH	User I/O
TDO	BST output; may float or be connected to TDI of another device	User I/O

3.4.10 TRST Pin and TAP Controller Reset

An active reset (TRST) pin is not supported; however, MX devices contain power-on circuitry that resets the boundary scan circuitry upon power-up. Also, the TMS pin is equipped with an internal pull-up resistor. This allows the TAP controller to remain in or return to the Test-Logic-Reset state when there is no input or when a logical 1 is on the TMS pin. To reset the controller, TMS must be HIGH for at least five TCK cycles.

3.4.11 Boundary Scan Description Language (BSDL) File

Conforming to the IEEE Standard 1149.1 requires that the operation of the various JTAG components be documented. The BSDL file provides the standard format to describe the JTAG components that can be used by automatic test equipment software. The file includes the instructions that are supported, instruction bit pattern, and the boundary-scan chain order. For an in-depth discussion on BSDL files, see the *BSDL Files Format Description* application note.

BSDL files are grouped into two categories - generic and device-specific. The generic files assign all user I/Os as inouts. Device-specific files assign user I/Os as inputs, outputs or inouts.

Generic files for MX devices are available on the Microsemi SoC Product Group's website:

http://www.microsemi.com/soc/techdocs/models/bsdl.html.

3.5 Development Tool Support

The MX family of FPGAs is fully supported by Libero® Integrated Design Environment (IDE). Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes SynplifyPro from Synopsys, ModelSim® HDL Simulator from Mentor Graphics® and Viewdraw.

Libero IDE includes place-and-route and provides a comprehensive suite of backend support tools for FPGA development, including timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor.

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

Table 14 • **Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to +70	–40 to +85	–55 to +125	°C
VCC (40MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCA (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V
VCCI (42MX)	4.75 to 5.25	4.5 to 5.5	4.5 to 5.5	V

Note: * Ambient temperature (T_A) is used for commercial and industrial grades; case temperature (T_C) is used for military grades.

3.7.1 5 V TTL Electrical Specifications

The following tables show 5 V TTL electrical specifications.

Table 15 • **5V TTL Electrical Specifications**

		Commercial		Commercial -F		Industrial		Military		
Symbol	**Parameter**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
VOH[1]	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					3.7		3.7		V
VOL[1]	IOL = 10 mA		0.5		0.5					V
	IOL = 6 mA						0.4		0.4	V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH (40MX)		2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	2.0	VCC + 0.3	V
VIH (42MX)[2]		2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	2.0	VCCI + 0.3	V
IIL	VIN = 0.5 V		–10		–10		–10		–10	µA
IIH	VIN = 2.7 V		–10		–10		–10		–10	µA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC[3]	A40MX02, A40MX04		3		25		10		25	mA
	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low power mode Standby Current	42MX devices only		0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0	mA
IIO, I/O source sink current	Can be derived from the *IBIS model* (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCC/VCCI = min
2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V

3.9.1 Mixed 5.0V/3.3V Electrical Specifications

Table 22 • **Mixed 5.0V/3.3V Electrical Specifications**

		Commercial		Commercial –F		Industrial		Military		
Symbol	**Parameter**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
VOH[1]	IOH = –10 mA	2.4		2.4						V
	IOH = –4 mA					2.4		2.4		V
VOL[1]	IOL = 10 mA		0.5		0.5					V
	IOL = 6 mA						0.4		0.4	V
VIL		–0.3	0.8	–0.3	0.8	–0.3	0.8	–0.3	0.8	V
VIH[2]		2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	2.0	VCCA + 0.3	V
IL	VIN = 0.5 V		–10		–10		–10		–10	µA
IH	VIN = 2.7 V		–10		–10		–10		–10	µA
Input Transition Time, T_R and T_F			500		500		500		500	ns
C_{IO} I/O Capacitance			10		10		10		10	pF
Standby Current, ICC[3]	A42MX09		5		25		25		25	mA
	A42MX16		6		25		25		25	mA
	A42MX24, A42MX36		20		25		25		25	mA
Low Power Mode Standby Current			0.5		ICC – 5.0		ICC – 5.0		ICC – 5.0	mA
IIO I/O source sink current	Can be derived from the *IBIS model* (http://www.microsemi.com/soc/techdocs/models/ibis.html)									

1. Only one output tested at a time. VCCI = min.
2. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V
3. All outputs unloaded. All inputs = VCCI or GND

3.9.2 Output Drive Characteristics for 5.0 V PCI Signaling

MX PCI device I/O drivers were designed specifically for high-performance PCI systems. Figure 16, page 28 shows the typical output drive characteristics of the MX devices. MX output drivers are compliant with the PCI Local Bus Specification.

Table 23 • **DC Specification (5.0 V PCI Signaling)[1]**

			PCI		MX		
Symbol	**Parameter**	**Condition**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
VCCI	Supply Voltage for I/Os		4.75	5.25	4.75	5.25[2]	V
VIH[3]	Input High Voltage		2.0	VCC + 0.5	2.0	VCCI + 0.3	V
VIL	Input Low Voltage		–0.5	0.8	–0.3	0.8	V
IIH	Input High Leakage Current	VIN = 2.7 V		70	—	10	µA
IIL	Input Low Leakage Current	VIN=0.5 V		–70	—	–10	µA
VOH	Output High Voltage	IOUT = –2 mA IOUT = –6 mA	2.4		 3.84		V
VOL	Output Low Voltage	IOUT = 3 mA, 6 mA		0.55	—	0.33	V

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (°\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (°\text{C})}{\theta_{ja}(°(\text{C/W}))} = \frac{150°\text{C} - 70°\text{C}}{(28°\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc}. A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (°\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (°\text{C})}{\theta_{jc}(°(\text{C/W}))} = \frac{150°\text{C} - 125°\text{C}}{(6.3°\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

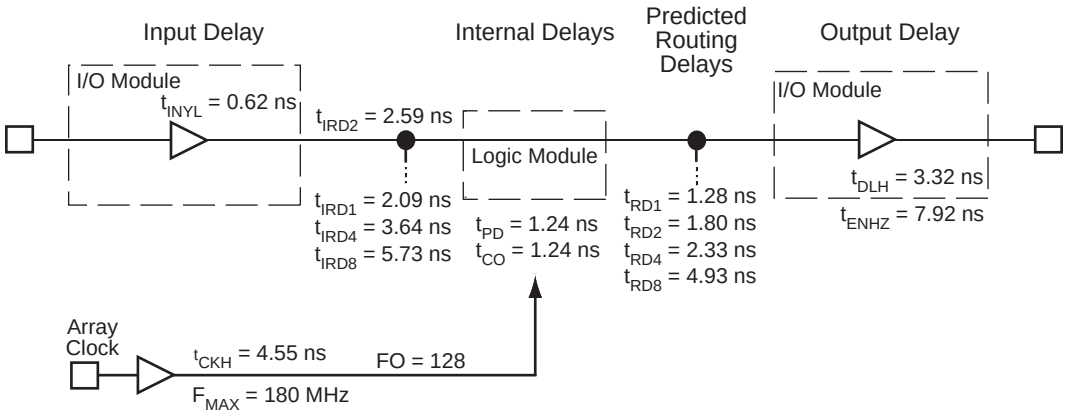
Table 27 • **Package Thermal Characteristics**

			θ_{ja}			
Plastic Packages	**Pin Count**	θ_{jc}	**Still Air**	**1.0 m/s 200 ft/min.**	**2.5 m/s 500 ft/min.**	**Units**
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	°C/W
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W

3.10 Timing Models

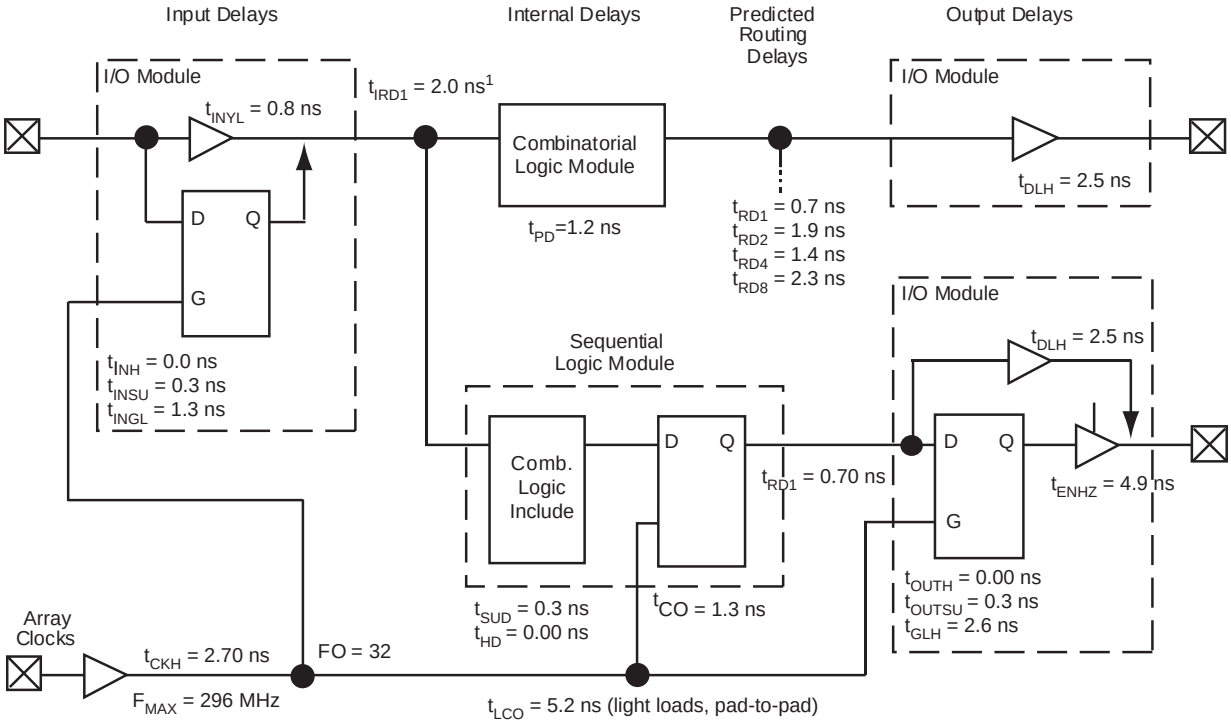
The following figures show various timing models.

Figure 17 • **40MX Timing Model***



Note: Values are shown for 40MX –3 speed devices at 5.0 V worst-case commercial conditions.

Figure 18 • **42MX Timing Model**



Note: 1. Input module predicted routing delay

Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

Figure 22 • **AC Test Loads**

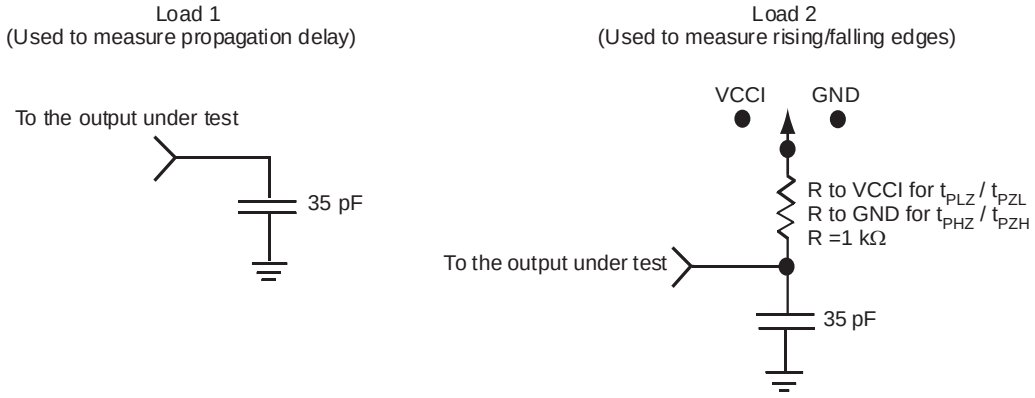


Figure 23 • **Input Buffer Delays**

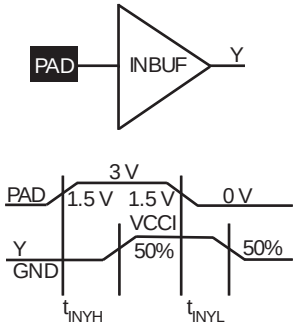


Figure 24 • **Module Delays**

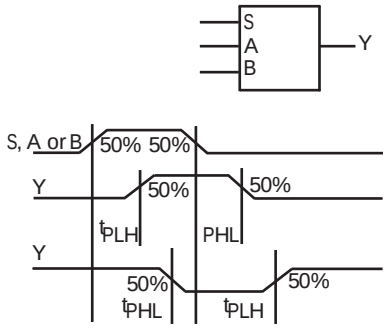


Table 36 • **A40MX04 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d_{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			1.0		1.2		1.3		1.6		2.2	ns
t_{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7	ns
t_{INGH}	G to Y HIGH			1.3		1.4		1.6		1.9		2.7	ns
t_{INGL}	G to Y LOW			1.3		1.4		1.6		1.9		2.7	ns
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.0		2.2		2.5		3.0		4.2	ns
t_{IRD2}	FO = 2 Routing Delay			2.3		2.5		2.9		3.4		4.7	ns
t_{IRD3}	FO = 3 Routing Delay			2.5		2.8		3.2		3.7		5.2	ns
t_{IRD4}	FO = 4 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t_{IRD8}	FO = 8 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32		2.4		2.7		3.0		3.6		5.0	ns
		FO = 256		2.7		3.0		3.4		4.0		5.5	ns
t_{CKL}	Input HIGH to LOW	FO = 32		3.5		3.9		4.4		5.2		7.3	ns
		FO = 256		3.9		4.3		4.9		5.7		8.0	ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t_{PWL}	Minimum Pulse Width LOW	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t_{CKSW}	Maximum Skew	FO = 32		0.3		0.3		0.4		0.5		0.6	ns
		FO = 256		0.3		0.3		0.4		0.5		0.6	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.3		2.6		3.0		3.5		4.9		ns
		FO = 256	2.2		2.4		3.3		3.9		5.5		ns
t_P	Minimum Period	FO = 32	3.4		3.7		4.0		4.7		7.8		ns
		FO = 256	3.7		4.1		4.5		5.2		8.6		ns
f_{MAX}	Maximum Frequency	FO = 32		296		269		247		215		129	MHz
		FO = 256		268		244		224		195		117	MHz

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		2.9		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t_{GLH}	G-to-Pad HIGH		4.2		4.6		5.2		6.1		8.6	ns
t_{GHL}	G-to-Pad LOW		4.2		4.6		5.2		6.1		8.6	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.6		1.8		2.1		2.5		3.5	ns
t_{CO}	Sequential Clock-to-Q		1.8		2.0		2.3		2.7		3.8	ns
t_{GO}	Latch G-to-Q		1.7		1.9		2.1		2.5		3.5	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		2.0		2.2		2.5		2.9		4.1	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		1.0		1.1		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO = 3 Routing Delay		1.6		1.8		2.0		2.4		3.3	ns

Table 41 • **A42MX16 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{ACO}	Array Clock-to-Out (Pad-to-Pad),64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros use tPD1 + tRD1 + taped, to + tRD1 + taped, or tPD1 + tRD1 + tusk, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing ansalysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 42 • **A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions[1]												
t_{PD}	Internal Array Module Delay		1.2		1.3		1.5		1.8		2.5	ns
t_{PDD}	Internal Decode Module Delay		1.4		1.6		1.8		2.1		3.0	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.7	ns
t_{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns
t_{RD3}	FO = 3 Routing Delay		1.3		1.4		1.6		1.9		2.6	ns
t_{RD4}	FO = 4 Routing Delay		1.5		1.7		1.9		2.2		3.1	ns
t_{RD5}	FO = 8 Routing Delay		2.4		2.7		3.0		3.6		5.0	ns
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.2		1.3		1.5		1.8		2.5	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.4		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.4		1.6		1.8		2.1		2.9	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.3		6.5		9.0		ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t_{IRD2}	FO = 2 Routing Delay			3.2		3.5		4.1		4.8		6.7	ns
t_{IRD3}	FO = 3 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
t_{IRD4}	FO = 4 Routing Delay			4.2		4.6		5.3		6.2		8.7	ns
t_{IRD8}	FO = 8 Routing Delay			6.1		6.8		7.7		9.0		12.6	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32 FO = 635		4.6 5.0		5.1 5.6		5.7 6.3		6.7 7.4		9.3 10.3	ns ns
t_{CKL}	Input HIGH to LOW	FO = 32 FO = 635		5.3 6.8		5.9 7.6		6.7 8.6		7.8 10.1		11.0 14.1	ns ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 635	2.5 2.8		2.7 3.1		3.1 3.5		3.6 4.1		5.1 5.7		ns ns
t_{PWL}	Minimum Pulse Width LOW	FO = 32 FO = 635	2.5 2.8		2.7 3.1		3.1 3.5		3.6 4.1		5.1 5.7		ns ns
t_{CKSW}	Maximum Skew	FO = 32 FO = 635		1.0 1.0		1.2 1.2		1.3 1.3		1.5 1.5		2.2 2.2	ns ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32 FO = 635	0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		0.0 0.0		ns ns
t_{HEXT}	Input Latch External Hold	FO = 32 FO = 635	4.0 4.6		4.4 5.2		5.0 5.9		5.9 6.9		8.2 9.6		ns ns
t_P	Minimum Period ($1/f_{MAX}$)	FO = 32 FO = 635	9.2 9.9		10.2 11.0		11.1 12.0		12.7 13.8		21.2 23.0		ns ns
f_{MAX}	Maximum Datapath Frequency	FO = 32 FO = 635		108 100		98 91		90 83		79 73		47 44	MHz MHz
TTL Output Module Timing[5]													
t_{DLH}	Data-to-Pad HIGH			3.6		4.0		4.5		5.3		7.4	ns
t_{DHL}	Data-to-Pad LOW			4.2		4.6		5.2		6.2		8.6	ns
t_{ENZH}	Enable Pad Z to HIGH			3.7		4.2		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW			4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z			7.34		8.2		9.3		10.9		15.3	ns
TTL Output Module Timing[5]													
t_{ENLZ}	Enable Pad LOW to Z			6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH			4.9		5.5		6.2		7.3		10.2	ns
t_{GHL}	G-to-Pad LOW			4.9		5.5		6.2		7.3		10.2	ns
t_{LSU}	I/O Latch Output Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.9		8.8		10.0		11.8		16.5	ns

Figure 42 • **PQ144**

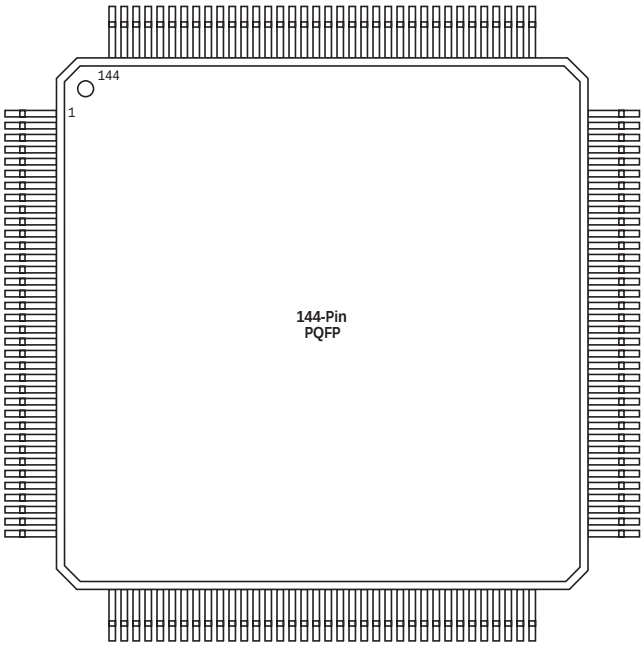


Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
169	I/O	WD, I/O	WD, I/O
170	I/O	I/O	I/O
171	NC	I/O	QCLKD, I/O
172	I/O	I/O	I/O
173	I/O	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	I/O	WD, I/O	WD, I/O
177	I/O	WD, I/O	WD, I/O
178	PRA, I/O	PRA, I/O	PRA, I/O
179	I/O	I/O	I/O
180	CLKA, I/O	CLKA, I/O	CLKA, I/O
181	NC	I/O	I/O
182	NC	VCCI	VCCI
183	VCCA	VCCA	VCCA
184	GND	GND	GND
185	I/O	I/O	I/O
186	CLKB, I/O	CLKB, I/O	CLKB, I/O
187	I/O	I/O	I/O
188	PRB, I/O	PRB, I/O	PRB, I/O
189	I/O	I/O	I/O
190	I/O	WD, I/O	WD, I/O
191	I/O	WD, I/O	WD, I/O
192	I/O	I/O	I/O
193	NC	I/O	I/O
194	NC	WD, I/O	WD, I/O
195	NC	WD, I/O	WD, I/O
196	I/O	I/O	QCLKC, I/O
197	NC	I/O	I/O
198	I/O	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	NC	I/O	I/O
202	VCCI	VCCI	VCCI
203	I/O	WD, I/O	WD, I/O
204	I/O	WD, I/O	WD, I/O
205	I/O	I/O	I/O

Table 55 • **VQ80**

VQ80		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
13	VCC	VCC
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	NC	I/O
18	NC	I/O
19	NC	I/O
20	VCC	VCC
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	GND	GND
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	VCC	VCC
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	NC	I/O
42	NC	I/O
43	NC	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	GND	GND
48	I/O	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
F2	I/O
F1	I/O
G1	I/O
G4	VSV
H1	I/O
H2	I/O
H3	I/O
H4	I/O
J1	I/O
K1	I/O
L1	I/O
K2	I/O
M1	I/O
K3	I/O
L2	I/O
N1	I/O
L3	BININ
M2	BINOUT
N2	I/O
M3	I/O
L4	I/O
N3	I/O
M4	I/O
N4	I/O
M5	I/O
K6	I/O
N5	I/O
N6	I/O
L6	I/O
M6	I/O
M7	I/O
N7	I/O
N8	I/O
M8	I/O
L8	I/O
K8	I/O
N9	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
G12	VSV
F13	I/O
F12	I/O
F11	I/O
F10	I/O
E13	I/O
D13	I/O
D12	I/O
C13	I/O
B13	I/O
D11	I/O
C12	I/O
A13	I/O
C11	I/O
B12	SDI
B11	I/O
C10	I/O
A12	I/O
A11	I/O
B10	I/O
D8	I/O
A10	I/O
C8	I/O
A9	I/O
B8	PRBA
A8	I/O
B7	CLKA
A7	I/O
B6	CLKB
A6	I/O
C6	PRBB
A5	I/O
D6	I/O
A4	I/O
B4	I/O
A3	I/O
C4	I/O

Figure 53 • **CQ172**

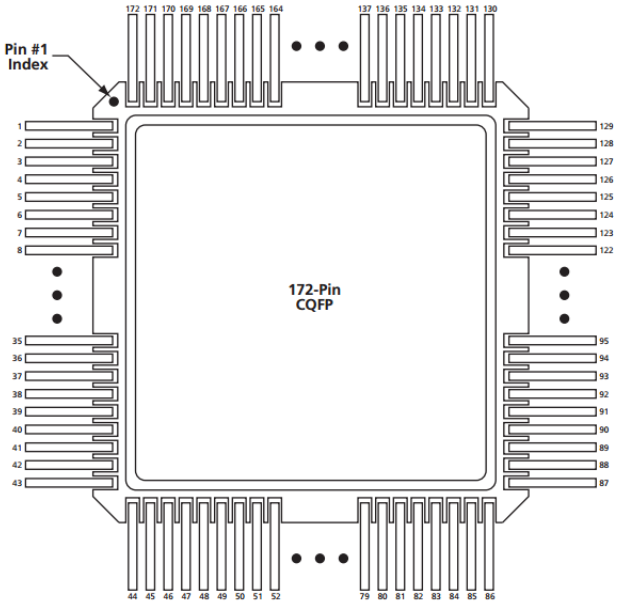


Table 62 • **CQ172**

CQ172	
Pin Number	**A42MX16 Function**
1	MODE
2	I/O
3	I/O
4	I/O
5	I/O
6	I/O
7	GND
8	I/O
9	I/O
10	I/O
11	I/O
12	VCC
13	I/O
14	I/O
15	I/O
16	I/O
17	GND
18	I/O
19	I/O
20	I/O